

**Search Notes**

Application/Control No.

10/813,161

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

CARR, CHARLES D.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	51,88,90 91 and 97	8/15/2005	JDS
216	24	8/16/2005	JDS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	8/15/2005	JDS
IEEE and INSPEC: optical, alignment, rotate, slide, plate, slab, substrate, bench, etching, tolerance	8/15/2005	JDS
PLUS keyword search	8/15/2005	JDS